Solar Probe Plus

A NASA Mission to Touch the Sun

Integrated Science Investigation of the Sun Energetic Particles



Preliminary Design Review 05 – 06 NOV 2013

EPI-Lo Mechanical

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Outline

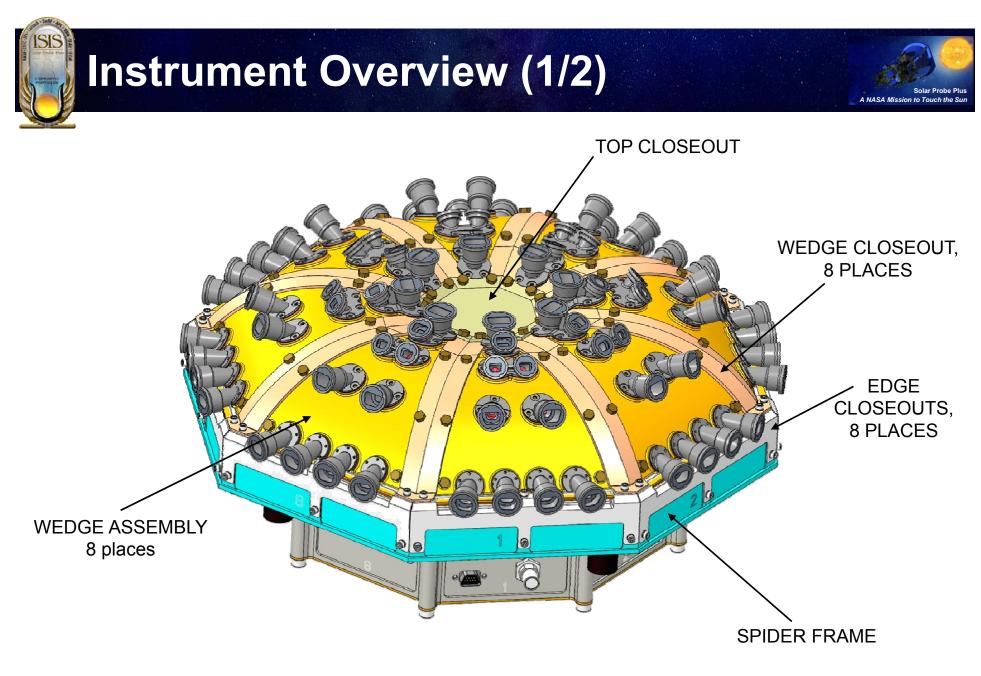


- Summary of mechanical design requirements
- Overview of mechanical design
- Detailed description of the instrument mechanical design
 - Wedge Assembly
 - MCP Assembly
 - SSD Assembly
- Assembly process
- Mechanical development status
- Summary of analyses
- Summary of Peer Review results

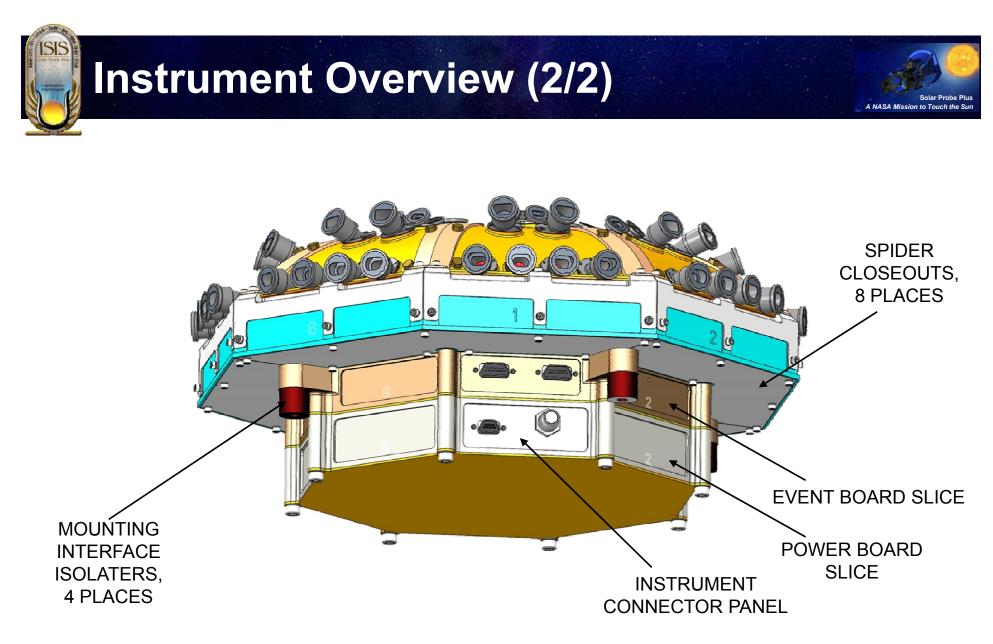
Mechanical Design Requirements



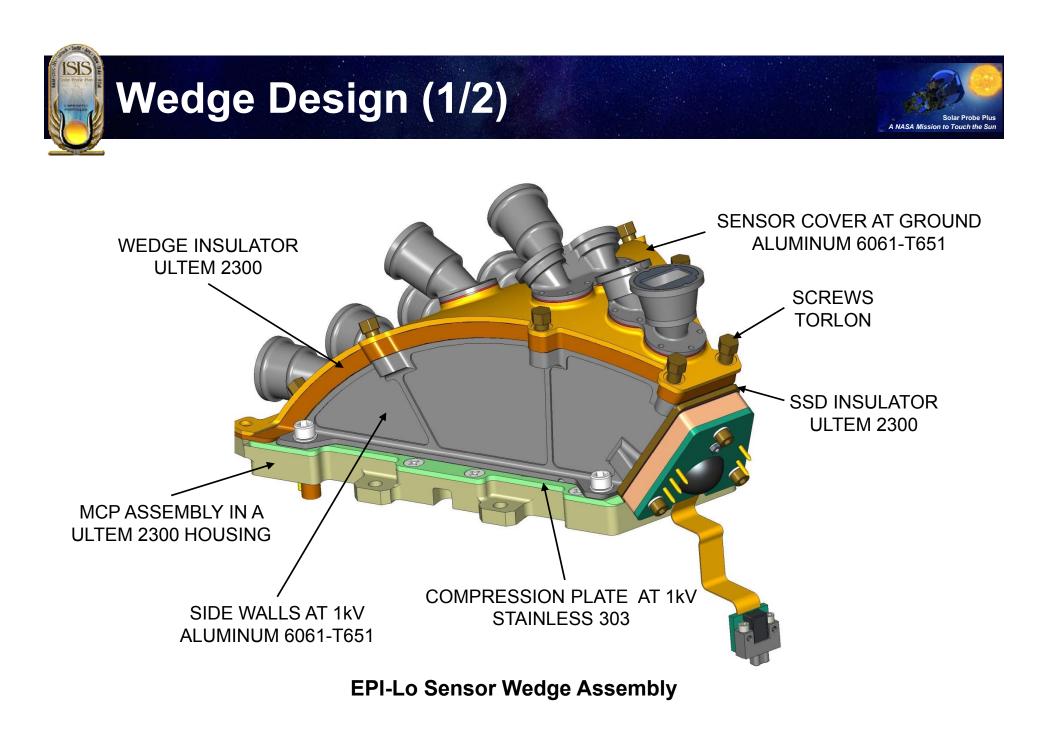
- Subsystem to have min frequency >80 Hz
- PWAs to have min frequency >150 Hz
- Quasi-static load factor: 40 g (Figure 4-11 & Table 4-19)
- Factors of safety: Table 4-5, Unpressurized Factors of Safety
- Random vibration levels: Table 4-8 and Table 4-9
- 7464-0008 EPI-Lo-S/C Mechanical ICD
 - Generated by EPI-Lo to document placement and orientation of instrument on spacecraft

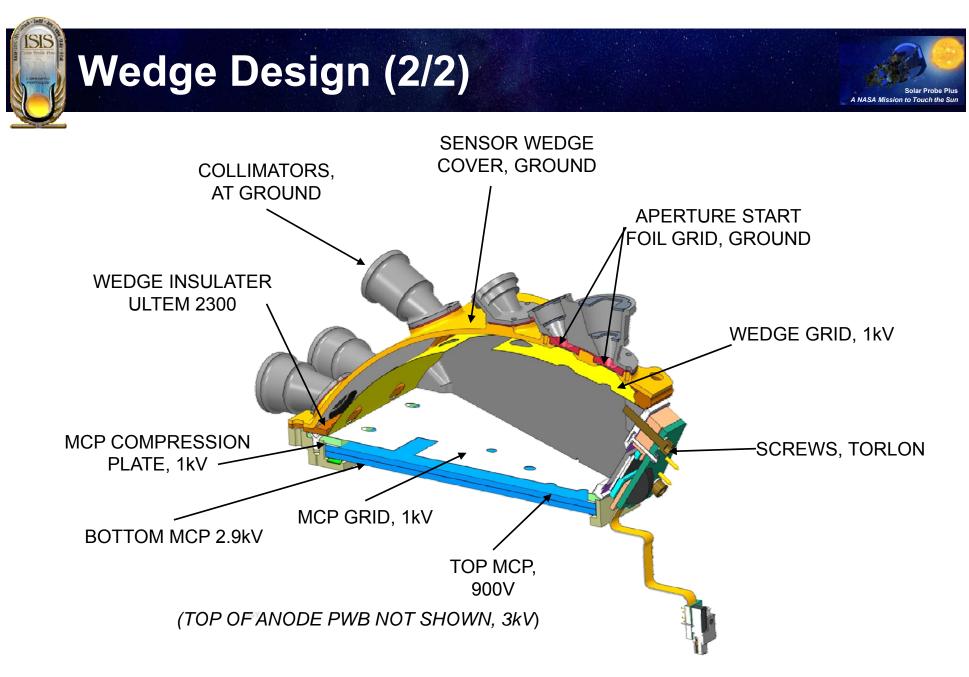


EPI-Lo Instrument Isometric View

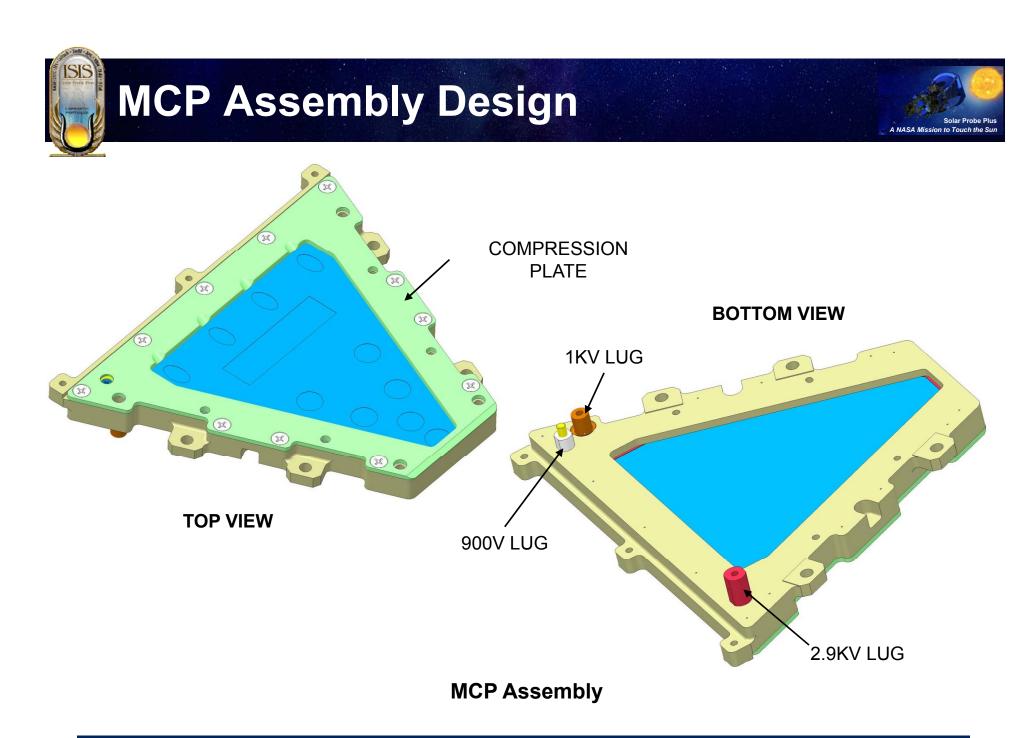


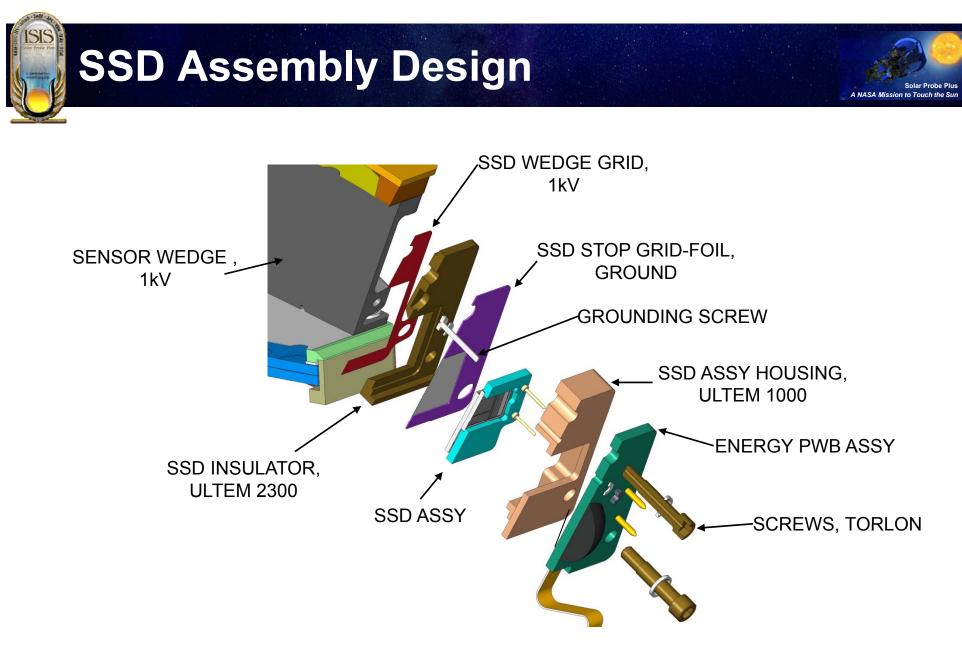
EPI-Lo Instrument Side Isometric View





EPI-Lo Sensor Wedge Assembly Cross-Section View

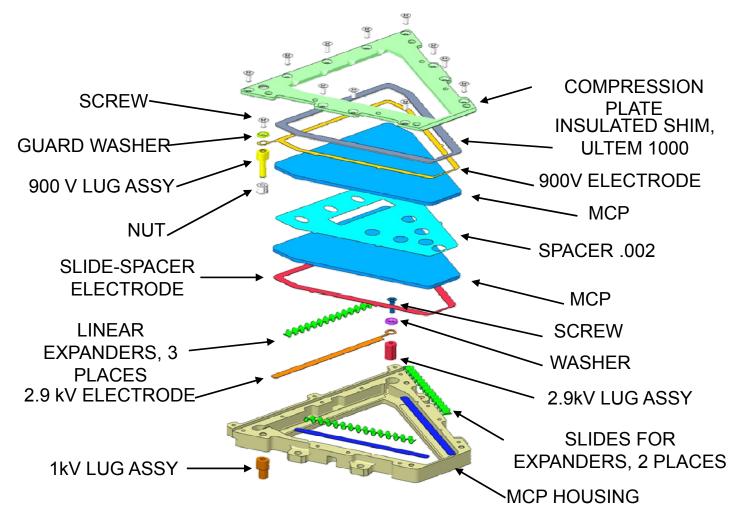




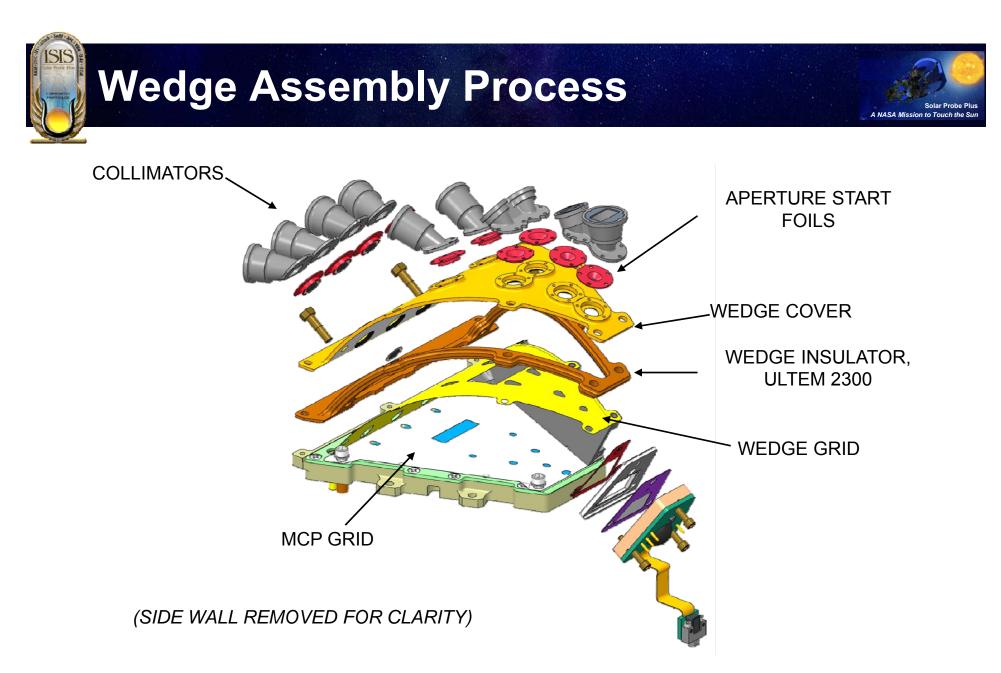
SSD Assembly Exploded Cross-Section View



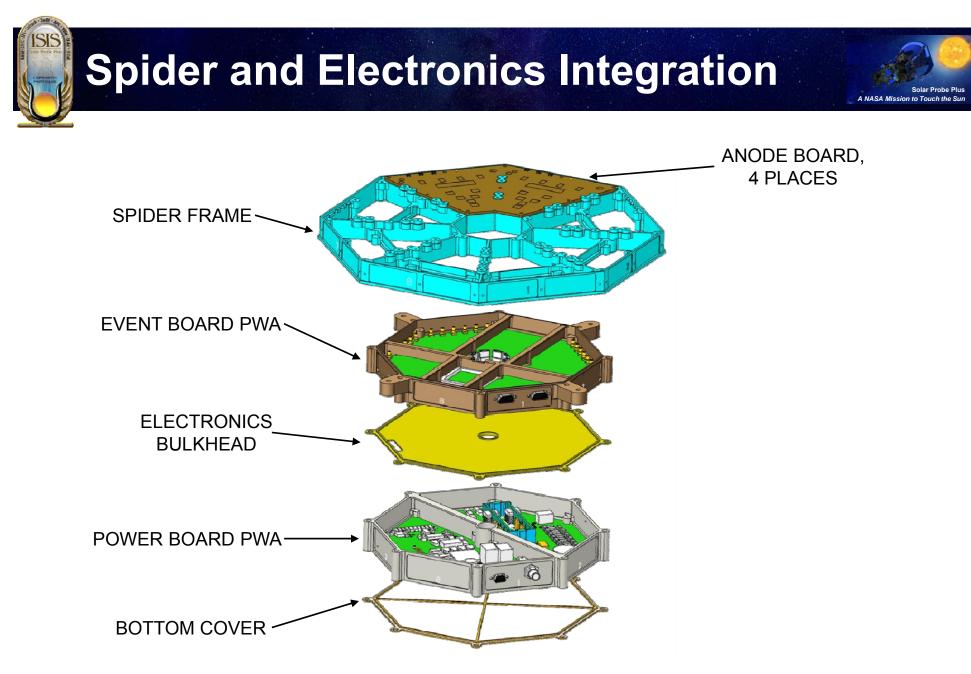




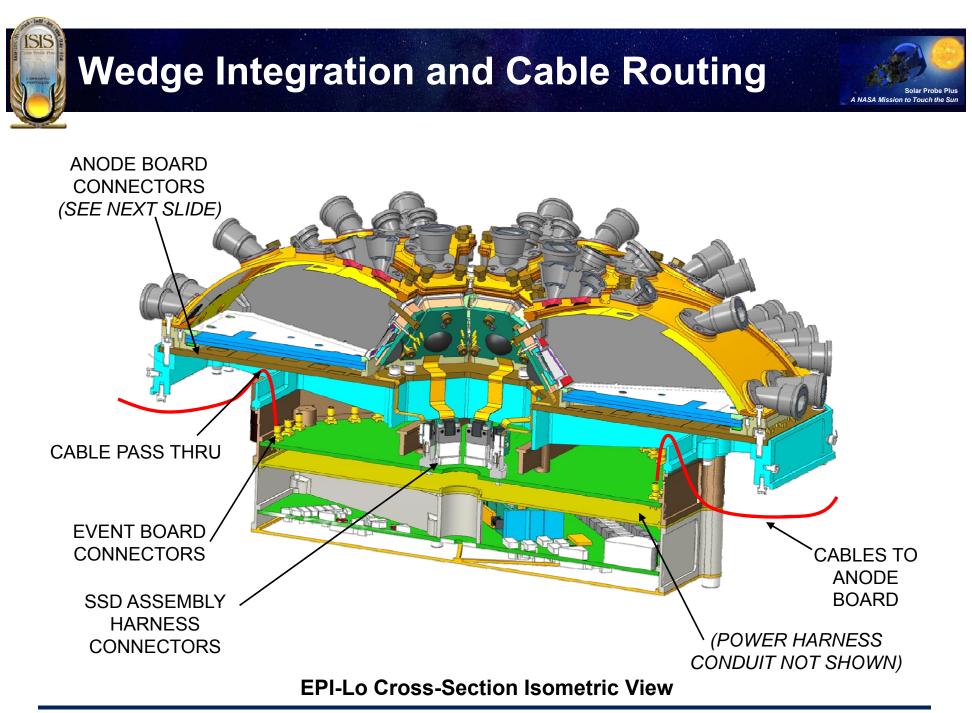
MCP Assembly Exploded View

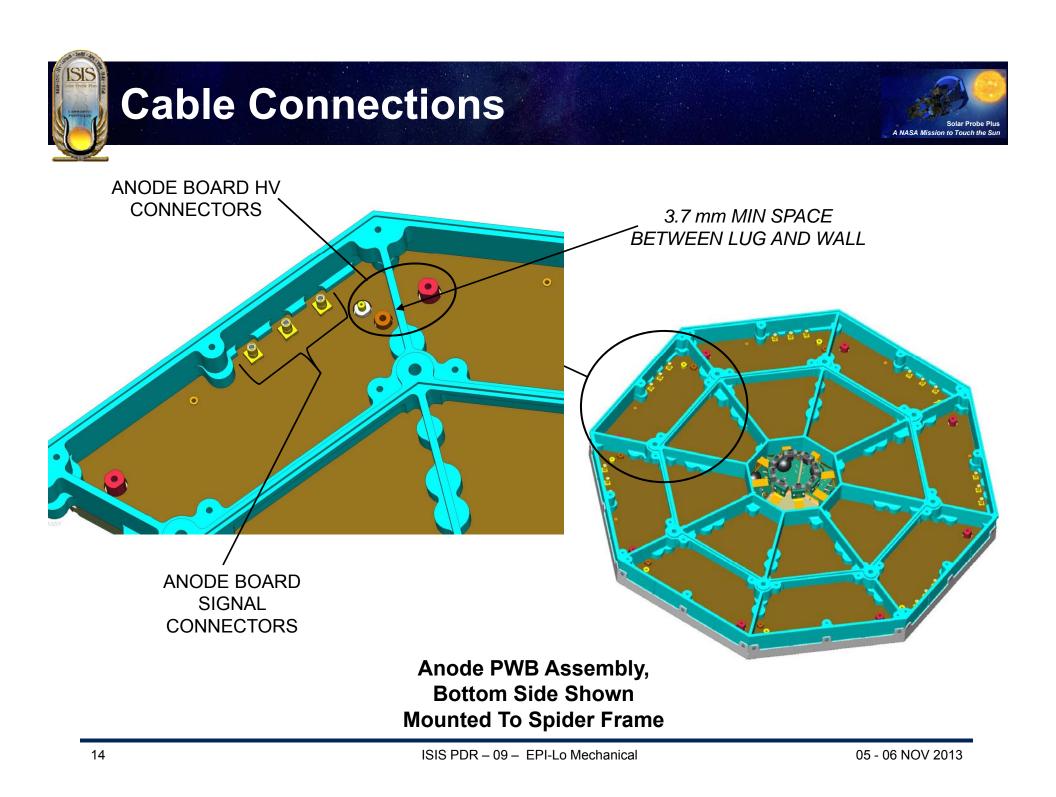


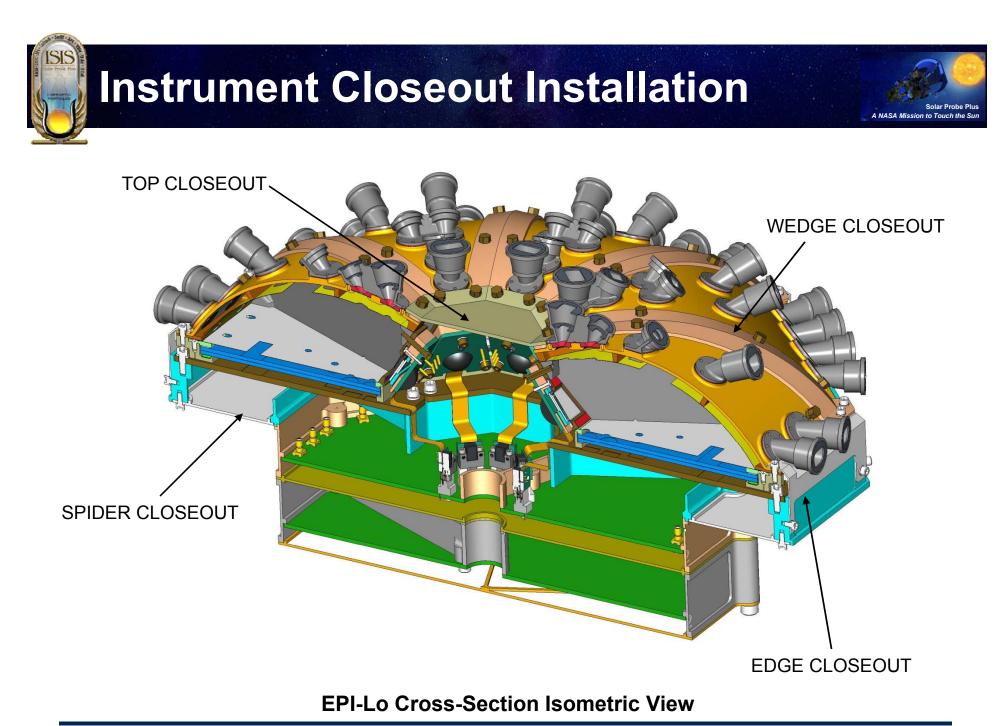
EPI-Lo Sensor Wedge Assembly Exploded View



EPI-Lo Electronics Frames Exploded View



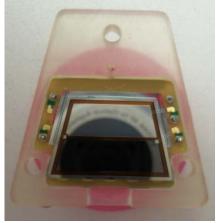


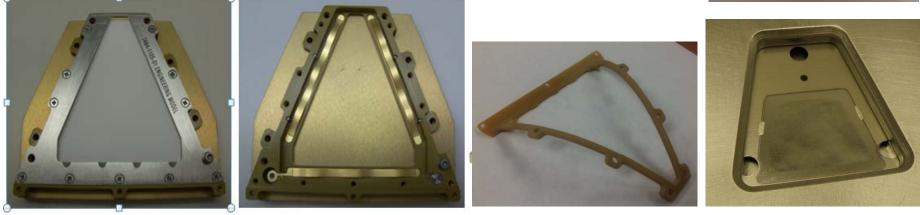


Development Status

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- Prototype sensor fully assembled and tested
- EM sensor
 - EM MCPs in house
 - EM SSDs in house and mounted to carrier
 - MCP holder with all electrodes assembled and tested at HV with ceramic plates
 - All EM grids and foils procured and in-house
 - Upper sensor parts in fabrication
 - Side walls, top cover, collimators





Mechanical – Path Forward

- Sensor EM testing
 - Test MCP assembly with MCPs and EM anode board
 - Assemble upper sensor parts
 - Test sensor wedge
 - Start and stop secondary electron locations
 - Timing performance
 - Integrate SSD to sensor wedge
 - Full performance testing with source and in APL accelerator
- Instrument-level EM testing
 - Fabricate chassis and e-box frames
 - Vibration testing with bracket, EPI-Hi mass model, two sensor wedges and other wedges as mass models
 - Acoustics testing with bracket, EPI-Hi mass model, two sensor wedges and other wedges as mass models
 - Thermal testing (simplified model representing outer surface)

Preliminary Analysis Results

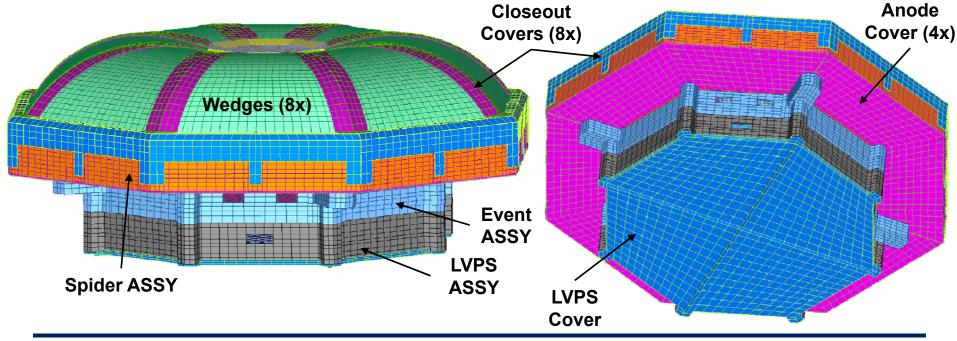


- SPP EPI-Lo instrument analyzed
 - Created from EPI-Lo CAD model as of 6/19/2013 SPP configuration
 - Instrument orientation to S/C panel taken from ISIS bracket CAD model: 4/19/2013
 - Instrument mass estimated at 2.99 kg (6.58 lbm)
- Structural model analyzed based on 7434-9039 SPP EDTRD requirements
 - Modal frequencies of assembly
 - Quasi-static design limit load per EDTRD Section 4.4.2.1 and 4.4.7.1
 - Random vibration analysis per EDTRD Section 4.4.3
 - Grms acceleration response for various components of the assembly
 - Peak 3-σ stress and displacement results

SIS

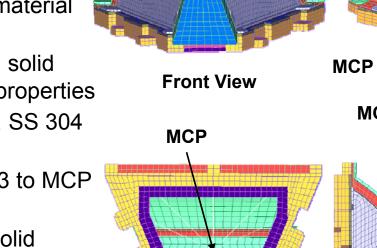
FEM Overview - Instrument Level

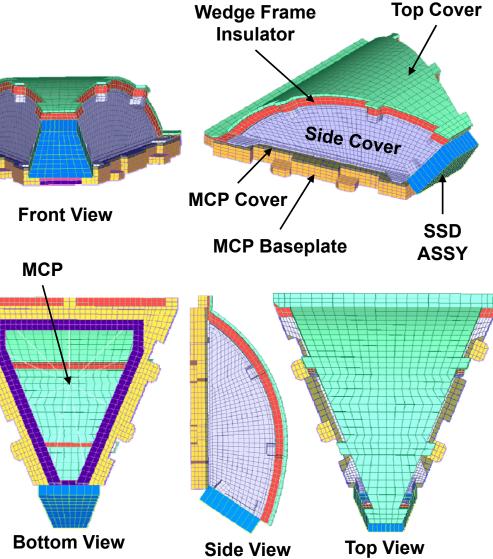
- Modeling Strategy
 - Plate elements where applicable: PWAs, frames, covers
 - Solid elements where necessary: frame bosses, bookbolt bosses, small aspect ratios
 - Beam elements: chassis ribs, LVPS bottom cover ribs
 - PWA: EEE part mass smeared over total board area
 - Rigid elements (RBE2s): bookbolts, mounting hardware, Connectors
- Model size: nodes = 89,077, elements = 70,645



FEM Overview - Wedge Assembly

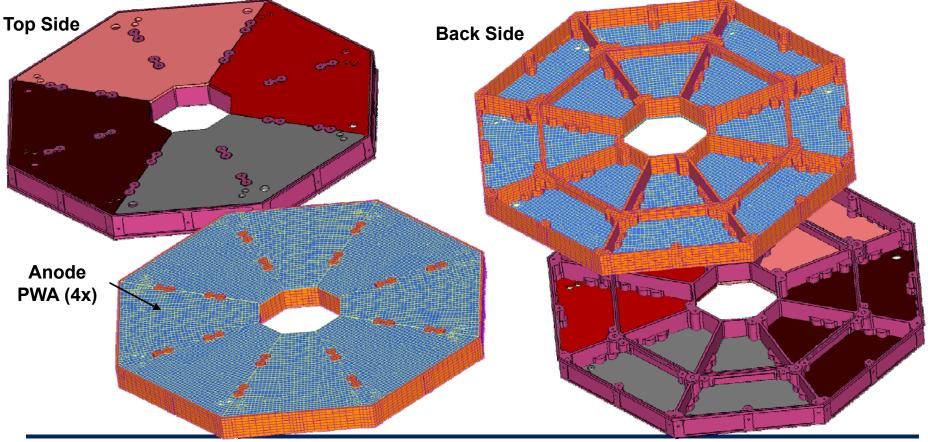
- EPI-Lo has 8 identical wedges
- Top cover: plate elements, AI-6061 properties & collimator mass smear
- Wedge Frame Insulator: plate and solid elements, Ultem1000 material properties
- Side cover: beam, plate and solid elements, AI-6061 material properties
- MCP Cover: plate elements, SS 304 properties
- MCP: mass element & RBF3 to MCP. cover and baseplate
- MCP Baseplate: plate and solid elements. Ultem100 material properties
- SSD Assembly: plate elements, Ultem100 material properties
- Wedge assembly connected using RBE2s at all bolted interfaces





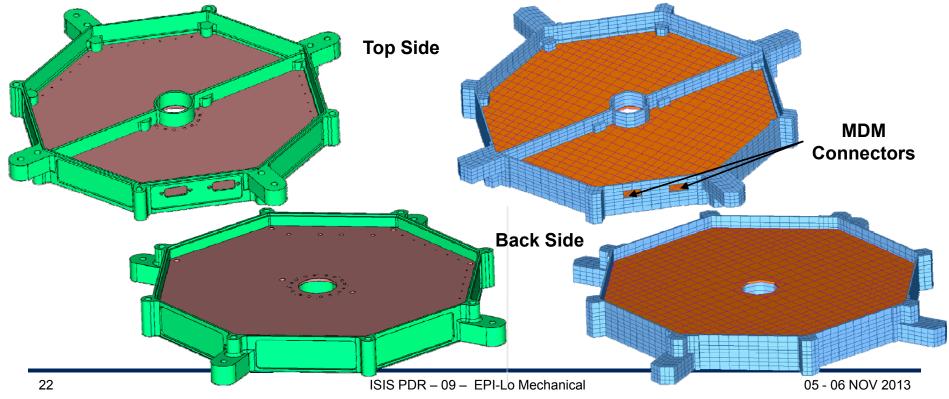
FEM Overview - Spider & Anode PWAs

- Spider frame modeled in detail using plate and solid elements with AI 6061 material properties
- Anode PWAs (4x) modeled using plate elements and PWA material properties with estimated board mass smeared across PWA
- PWAs connected to Spider frame at mounting hardware bosses using RBE2 elements



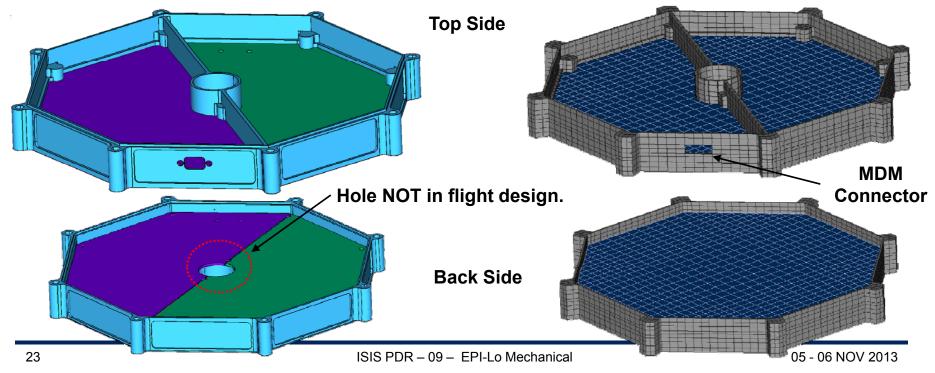
FEM Overview - Event Slice Assembly

- Event housing: plate and solid elements, AI 6061 material properties
- Event housing thickness .040" at minimum, thicker at bosses
- Event PWA: plate elements, PWA material properties and EEE part mass smeared across board
- PWA: diameter = 7.0", thickness = 0.093"
- Right-angle MDM connectors modeled with RBE2s from frame to board
- PWA connected to housing with RBE2s at mounting bosses



FEM Overview - LVPS Slice Assembly

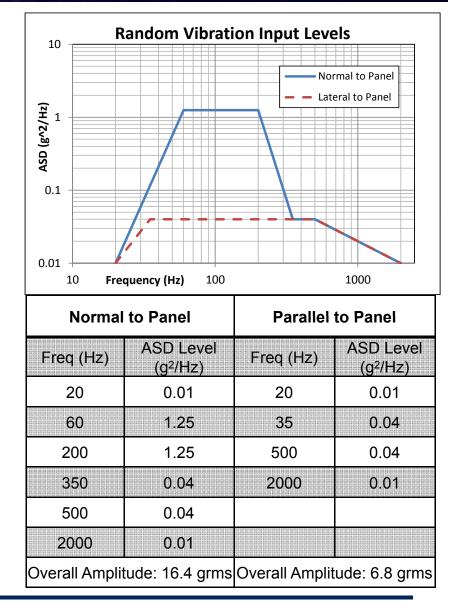
- LVPS housing: plate and solid elements, AI 6061 material properties
- LVPS housing thickness .040" at minimum, thicker at bosses
- LVPS PWA: plate elements, PWA material properties and EEE part mass smeared across board
- PWA: diameter = 7.0", thickness = 0.093"
- Right-angle MDM connector modeled with RBE2 from frame to board
- PWA connected to housing with RBE2s at mounting bosses
- CAD PWA model does not capture flight design, FEM representative of flight config.



Forced Response Analysis



- All relevant structural environmental inputs per 7434-9039 SPP EDTRD
- Assume critical damping = 2.5% across full frequency range
- Sine sweep spec per Section 4.4.4 is TBD, therefore not analyzed
- Random vibration levels per Section 4.4.3
 - Table 4-8, Side panel mounted components & subsystems parallel to panel
 - Table 4-9, Side panel mounted components & subsystems lateral to panel
- Items of interest for random response analysis:
 - Grms acceleration response of instrument and PWAs
 - Peak 3-σ displacement response
 - Peak 3-σ stress & margins of safety
- Random vibration analysis results envelope Static 40 g load (per Section 4.4.2.1)
- 40 g static load results not presented in this analysis



SIS

Forced Response Analysis Random Vibration Grms Results



- Random vibration inputs simulated at B.C. node
 - B.C. node "spidered" to nodes at instrument mounting interface to ISIS bracket
 - ISIS bracket and G-10 standoffs NOT part of EPI-Lo FEM, assume instrument "hard-mounted"
 - Inputs simulated one axis at a time for all three orthogonal axes
- Acceleration spectral density (ASD) response for various nodes
 - Nodes represent worst case response per subassembly
 - Across full range (20-2,000 Hz) of interest
- Due to EPI-Lo's mounting configuration in relation to the input load, there are significant cross-axes responses

Y-axis Inp	X-axis In			
ID	X-Axis	Y-axis	Z-Axis	ID
Input	0.0	16.4	0.0	Input
C.G.	7.8	67.9	8.1	C.G.
Event PWA	31.2	193.0	30.1	Event PWA
LVPS PWA	26.4	158.1	25.1	LVPS PWA
LVPS Cover	26.9	153.5	26.2	LVPS Cover
Top Cover	16.0	112.1	17.0	Top Cover
Anode PWA	9.4	76.5	10.2	Anode PWA
Anode Cover	12.2	92.3	12.8	Anode Cover
Spider Frame	5.5	66.1	9.5	Spider Frame

X-axis Input 3-σ grms Response

Y-axis

0.0

7.8

41.4

97.9

30.5

16.3

61.5

161.1

64.0

Z-Axis

0.0

3.4

8.0

27.4

14.8

56

10.3

27.0

12.1

X-Axis

6.8

30.9

26.2

48.9

45.7

58.0

30.8

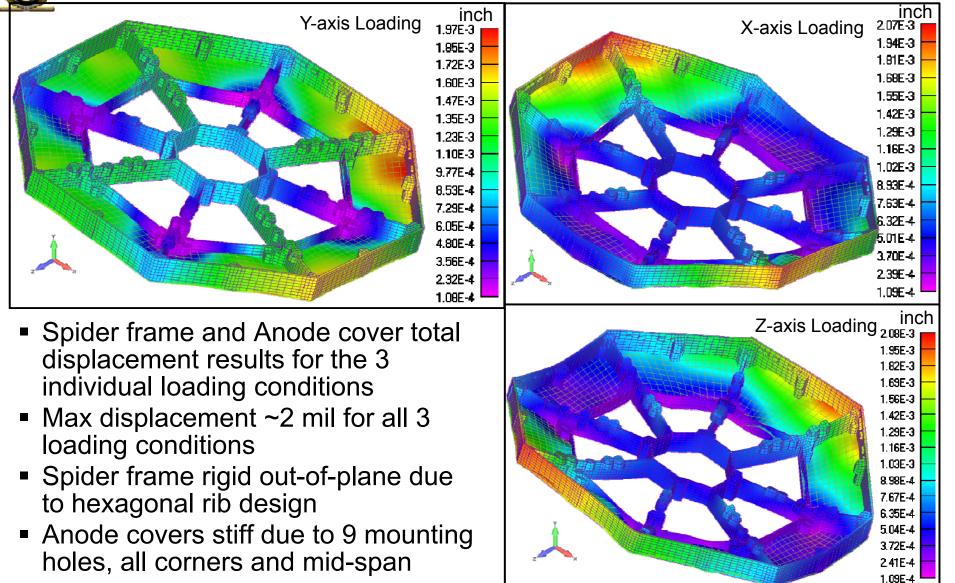
35.7

29.9

Z-axis Input 3-σ grms Response

ID	X-Axis	Y-axis	Z-Axis
Input	0.0	0.0	6.8
C.G.	3.4	8.2	31.3
Event PWA	13.6	64.7	29.4
LVPS PWA	24.1	71.9	46.5
LVPS Cover	14.2	27.7	50.9
Top Cover	5.6	17.0	57.9
Anode PWA	11.8	65.4	33.9
Anode Cover	13.1	67.3	26.8
Spider Frame	8.7	28.1	31.4

Forced Response Analysis Random Vibration Results: Displacement



Forced Response Analysis Random Vibration Results: von Mises Stresser

- Model analyzed for von Mises stress under random vibration loading using MAYA structural analysis toolkit
- 3-σ stress results output for complete model
- Interested mainly in PWA and Frame stress
- Fastener analysis not done at this time
- Factors of safety (FoS) taken from 7434-9039 SPP EDTRD Rev E, Table 4-5.
 - Additional 1.28 factor for random analysis per Section 4.4.2.2
 - Metallic structures: FoSu = 2.68, FoSy = 2.53
 - Composite (PWA + Ultem1000): FoSu = 2.78, FoSy = N/A
- Margins of safety (MoS) calculations performed,
 - MoS formula -> $MoS = \frac{Strength}{FoS^*\sigma} 1$
- All margin of safety results are positive for the current design iteration

Analysis Summary



- Preliminary structural analysis of the baseline SPP EPI-Lo Instrument performed
- MSC.Nastran, MAYA SATK, and Femap used for analysis
 - Model simplified wherever possible to aid solution time
 - PWAs modeled as plate elements with uniform stiffness, thickness and density
 - Instrument model oriented to ISIS bracket configuration in relation to S/C panel
- Modal analysis performed, 1st mode = 304 Hz (Event PWA); Instrument mode 1 = 553 Hz
- Analysis environmental input levels per 7434-9039 SPP EDTRD Rev -
 - Analysis performed for all three orthogonal axes relative to S/C panel
 - Sine vibration analysis not performed (TBD in EDTRD)
 - EPI-Lo 3-σ acceleration random response enveloped static load requirement
 - Random vibration analysis 3-σ response desired for EPI-Lo instrument displacements, stresses and forces
- Random vibration PWA displacement response may be relatively high for EEE part solder/lead wire fatigue resistance, further analysis needed after EEE parts placement finalized
- All margin of safety positive for model configuration as of 6/19/13 under EDTRD Rev - inputs
- Detailed analysis needed for the flight configuration to confirm that flight design will have positive margins and meet minimum frequency requirement

Instrument Peer Review



- EPI-Lo Sensor Peer Review
 - Held May 22, 2013 at APL
 - Review yielded 12 action items, all are now closed
- EPI-Lo Instrument Peer Review
 - Held August 19, 2013 at APL
 - Review yielded 8 mechanical action items, all are now closed